

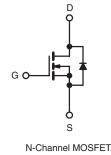
# K1307-VB Datasheet N-Channel 100-V (D-S) MOSFET

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	100				
R <sub>DS(on)</sub> (Ω)	V <sub>GS</sub> = 10 V	0.086			
Q <sub>g</sub> (Max.) (nC)	72				
Q <sub>gs</sub> (nC)	11				
Q <sub>gd</sub> (nC)	32				
Configuration	Single				

### **FEATURES**

- Isolated Package
- High Voltage Isolation = 2.5 kV<sub>RMS</sub> (t = 60 s; f = 60 Hz)
- Sink to Lead Creepage Distance = 4.8 mm
- 175 °C Operating Temperature
- Dynamic dV/dt Rating
- Low Thermal Resistance
- Lead (Pb)-free Available





ABSOLUTE MAXIMUM RATINGS T	<sub>C</sub> = 25 °C, unless otherw	vise noted			
PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage	V <sub>DS</sub>	100	v		
Gate-Source Voltage	V <sub>GS</sub>	± 20	V		
Continuous Drain Current	$V_{GS} \text{ at } 10 \text{ V} \qquad T_{C} = 25 \text{ °C} \\ T_{C} = 100 \text{ °C} $		18		
	$V_{GS}$ at 10 V $T_C = 100 ^{\circ}C$	ID	12	А	
Pulsed Drain Current <sup>a</sup>	I <sub>DM</sub>	68	1		
Linear Derating Factor			0.32	W/°C	
Single Pulse Avalanche Energy <sup>b</sup>	E <sub>AS</sub>	720	mJ		
Repetitive Avalanche Current <sup>a</sup>	I <sub>AR</sub>	17	A		
Repetitive Avalanche Energy <sup>a</sup>	E <sub>AR</sub>	4.8	mJ		
Maximum Power Dissipation	T <sub>C</sub> = 25 °C	PD	48	W	
Peak Diode Recovery dV/dt <sup>c</sup>	dV/dt	5.5	V/ns		
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 55 to + 175	°C	
Soldering Recommendations (Peak Temperature)	for 10 s		300 <sup>d</sup>		
Mounting Torque	6-32 or M3 screw		10	lbf ⋅ in	
	0-52 OF WIS SCIEW		1.1	N ⋅ m	

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b.  $V_{DD} = 25 \text{ V}$ , starting  $T_J = 25 \text{ °C}$ , L = 3.7 mH,  $R_G = 25 \Omega$ ,  $I_{AS} = 17 \text{ A}$  (see fig. 12). c.  $I_{SD} \le 17 \text{ A}$ , dl/dt  $\le 200 \text{ A}/\mu\text{s}$ ,  $V_{DD} \le V_{DS}$ ,  $T_J \le 175 \text{ °C}$ .

d. 1.6 mm from case.



COMPLIANT

1



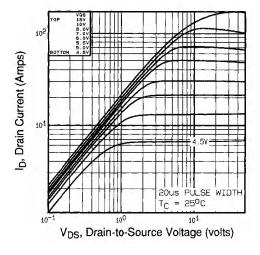
THERMAL RESISTANCE RAT	TINGS							
PARAMETER	SYMBOL	ТҮР	•	MAX.		UNIT		
Maximum Junction-to-Ambient	R <sub>thJA</sub>	- 65			°C/M			
Maximum Junction-to-Case (Drain)	R <sub>thJC</sub>	- 3.1				°C/W		
	unloss othory	viso notod						
<b>SPECIFICATIONS</b> $T_J = 25 \text{ °C}$ , PARAMETER	SYMBOL	1		ONS	MIN.	TYP.	MAX.	UNIT
Static	STMDOL			0113			WAA.	UNIT
Drain-Source Breakdown Voltage	V <sub>DS</sub>	Vee -	= 0 V, I <sub>D</sub> = 2	50 114	100	-	-	V
V <sub>DS</sub> Temperature Coefficient	ΔV <sub>DS</sub> /T <sub>J</sub>		e to 25 °C,	-	-	0.13	_	V/°C
Gate-Source Threshold Voltage	50 0		= V <sub>GS</sub> , I <sub>D</sub> = 2		1.0	0.10	3.0	V/ C
Gate-Source Leakage	V <sub>GS(th)</sub>				-	-	± 100	nA
Gale-Source Leakage	I <sub>GSS</sub>		$V_{GS} = \pm 20 \text{ V}$		-	-	± 100	IIA
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	-	$V_{DS} = 100 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$		-	-	250	μA
Drain-Source On-State Resistance	<b>D</b> <sub>-</sub>	$V_{DS} = 80 \text{ V}, \text{ V}_{GS} = 0 \text{ V}, \text{ T}_{J} = 150 \text{ °C}$ $V_{GS} = 10 \text{ V} \qquad \text{ I}_{D} = 10 \text{ A}^{\text{b}}$			-		250	Ω
Forward Transconductance	R <sub>DS(on)</sub>		= 50 V, I <sub>D</sub> =		- 9.1	0.086	-	S2
	9 <sub>fs</sub>	V DS -	= 50 v, 1 <sub>D</sub> =	10 A*	9.1	<u> </u>	-	3
Dynamic					<u> </u>	1700	[	1
Input Capacitance	Ciss	$V_{GS} = 0 V,$ $V_{DS} = 25 V,$ f = 1.0 MHz, see fig. 5		-	1700	-	pF	
Output Capacitance	C <sub>oss</sub>			-	560	-		
Reverse Transfer Capacitance	C <sub>rss</sub>			-	120	-		
Drain to Sink Capacitance	С		f = 1.0 MHz	2	-	12	-	
Total Gate Charge	Qg	-	lo = 17 /	A, V <sub>DS</sub> = 80 V,	-	-	72	
Gate-Source Charge	$Q_gs$	V <sub>GS</sub> = 10 V	see fig	J. 6 and 13 <sup>b</sup>	-	-	11	nC
Gate-Drain Charge	$Q_gd$				-	-	32	
Turn-On Delay Time	t <sub>d(on)</sub>				-	11	-	
Rise Time	t <sub>r</sub>	$V_{DD} = 50 \text{ V}, \text{ I}_D = 17 \text{ A},$ $R_G = 9.1 \Omega, R_D = 2.9 \Omega,$ see fig. $10^{\text{b}}$		-	44	-	ns	
Turn-Off Delay Time	t <sub>d(off)</sub>			-	53	-		
Fall Time	t <sub>f</sub>			-	43	-		
Internal Drain Inductance	L <sub>D</sub>	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	nH	
Internal Source Inductance	LS			-	7.5	-		
Drain-Source Body Diode Characteristic	s				•	•		1
Continuous Source-Drain Diode Current	I <sub>S</sub>	MOSFET symbol		-	-	17	A	
Pulsed Diode Forward Current <sup>a</sup>	I <sub>SM</sub>	integral reverse p - n junction diode			-	-		68
Body Diode Voltage	V <sub>SD</sub>	$T_J$ = 25 °C, $I_S$ = 17 A, $V_{GS}$ = 0 V <sup>b</sup>			-	-	2.5	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>	$T_J = 25 \ ^{\circ}C, I_F = 17 \ A, dI/dt = 100 \ A/\mu s^b$		-	180	360	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>			-	1.3	2.6	μC	
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by Ls and LD)					)	

#### Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width  $\leq$  300 µs; duty cycle  $\leq$  2 %.





TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



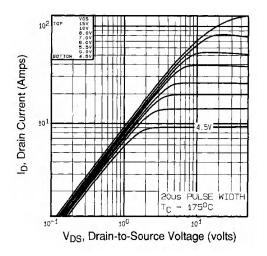


Fig. 2 - Typical Output Characteristics,  $T_C = 175 \ ^\circ C$ 

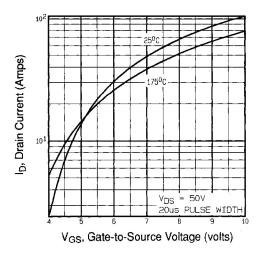


Fig. 3 - Typical Transfer Characteristics

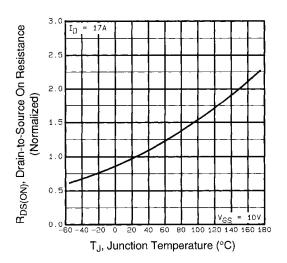


Fig. 4 - Normalized On-Resistance vs. Temperature

## K1307-VB



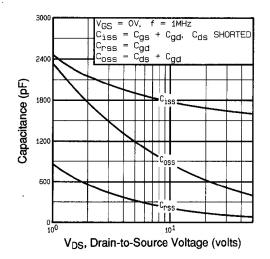


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

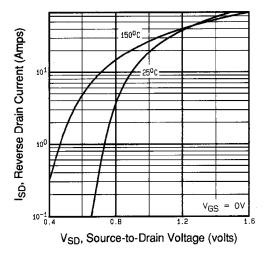


Fig. 7 - Typical Source-Drain Diode Forward Voltage

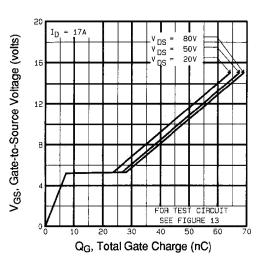


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

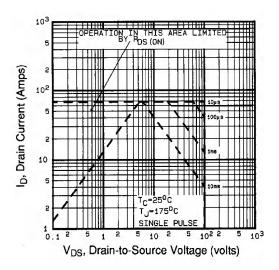


Fig. 8 - Maximum Safe Operating Area



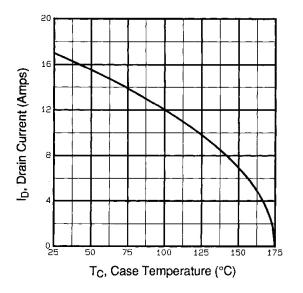


Fig. 9 - Maximum Drain Current vs. Case Temperature

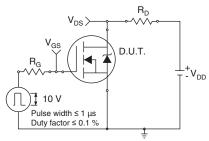


Fig. 10a - Switching Time Test Circuit

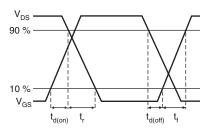


Fig. 10b - Switching Time Waveforms

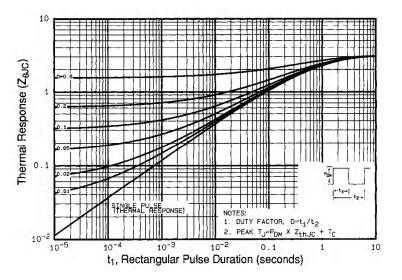


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

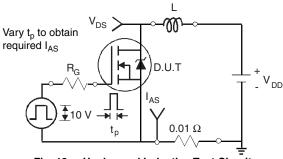


Fig. 12a - Unclamped Inductive Test Circuit

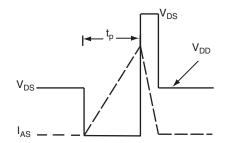


Fig. 12b - Unclamped Inductive Waveforms



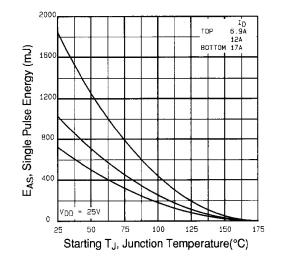


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

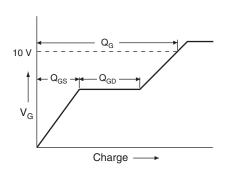
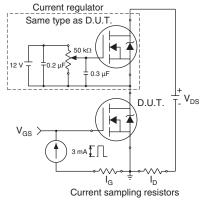
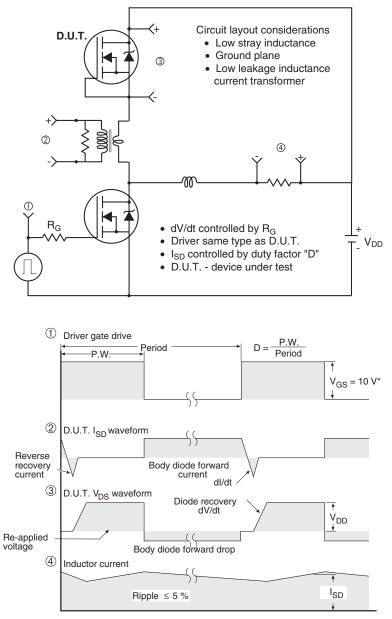


Fig. 13a - Basic Gate Charge Waveform









Peak Diode Recovery dV/dt Test Circuit

\*  $V_{GS}$  = 5 V for logic level devices

Fig.14 - For N-Channel



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